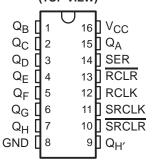
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- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Inputs Are TTL-Voltage Compatible
- 8-Bit Serial-In, Parallel-Out Shift Registers With Storage
- Independent Direct Overriding Clears on Shift and Storage Registers
- Independent Clocks for Both Shift and Storage Registers
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

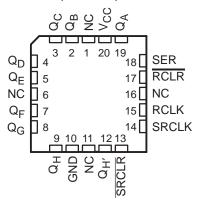
description

The 'AHCT594 devices contain an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. Separate clocks and direct overriding clear ($\overline{SRCLR}, \overline{RCLR}$) inputs are provided on both the shift and storage registers. A serial ($Q_{H'}$) output is provided for cascading purposes.

SN54AHCT594 . . . J OR W PACKAGE SN74AHCT594 . . . D, DB, N, OR PW PACKAGE (TOP VIEW)



SN54AHCT594 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

Both the shift register (SRCLK) and storage register (RCLK) clocks are positive edge triggered. If both clocks are connected together, the shift register always is one count pulse ahead of the storage register.

The SN54AHCT594 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74AHCT594 is characterized for operation from –40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

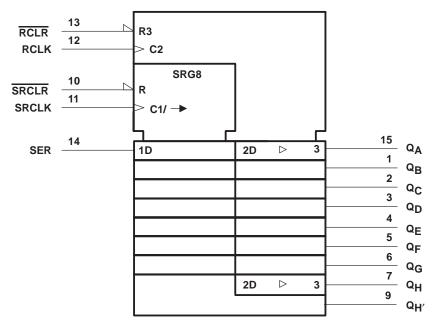
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FUNCTION TABLE

		INPUTS			FUNCTION
SER	SRCLK	SRCLR	RCLK	RCLR	FUNCTION
Х	Х	L	Х	Χ	Shift register is cleared.
L	1	Н	Х	Х	First stage of shift register goes low. Other stages store the data of previous stage, respectively.
Н	1	Н	Х	Х	First stage of shift register goes high. Other stages store the data of previous stage, respectively.
L	\downarrow	Н	Х	Х	Shift-register state is not changed.
Х	Χ	X	X	L	Storage register is cleared.
Х	Χ	X	\uparrow	Н	Shift-register data is stored in the storage register.
Х	Χ	X	\downarrow	Н	Storage-register state is not changed.

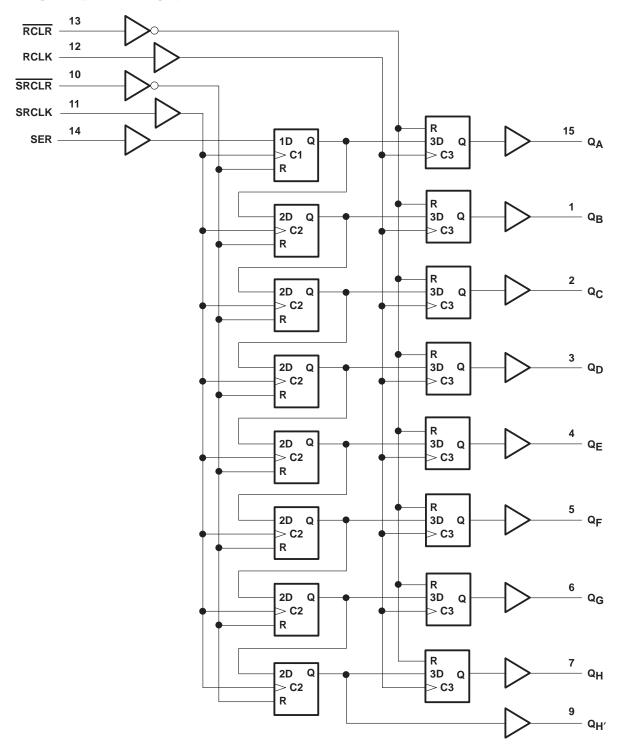
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, J, N, PW, and W packages.



logic diagram (positive logic)

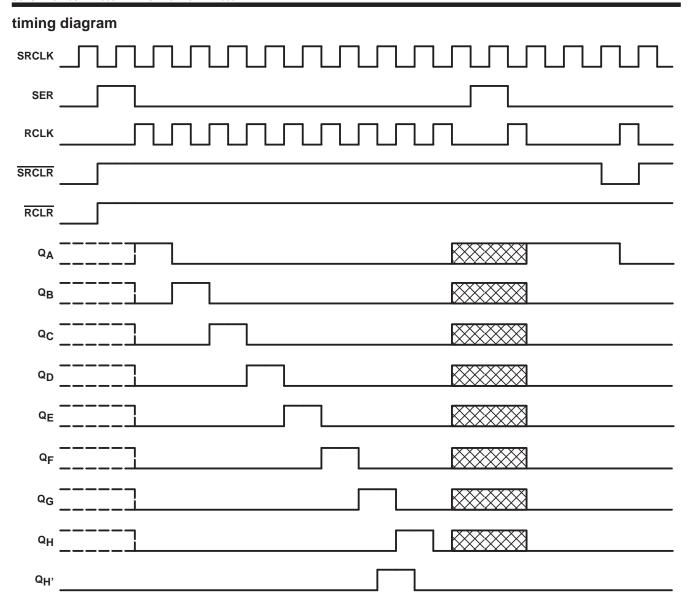


Pin numbers shown are for the D, DB, J, N, PW, and W packages.



SN54AHCT594, SN74AHCT594 8-BIT SHIFT REGISTERS WITH OUTPUT REGISTERS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		0.5 V to 7 V
Output voltage range, VO (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I _{IK} (V _I < 0)		–20 mA
Output clamp current, IOK (VO < 0 or VO > VCC	c)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})		±25 mA
Continuous current through V _{CC} or GND		±75 mA
Package thermal impedance, θ_{JA} (see Note 2):	D package	73°C/W
	DB package	82°C/W
	N package	67°C/W
	PW package	108°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

		SN54AHCT594		SN74AHCT594		UNIT
		MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2	V	2		V
V _{IL}	Low-level input voltage		0.8		0.8	V
٧ _I	Input voltage	0	5.5	0	5.5	V
Vo	Output voltage	0/	VCC	0	VCC	V
ІОН	High-level output current	27/	-8		-8	mA
lOL	Low-level output current	⁷ 0 ₄	8		8	mA
Δt/Δν	Input transition rise or fall rate	Q	20		20	ns/V
T _A	Operating free-air temperature	- 55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vac	T _A = 25°C			SN54AHCT594		SN74AHCT594		UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
Vo.,	I _{OH} = -50 μA	4.5 V	4.4	4.5		4.4		4.4		V
VOH	I _{OH} = -8 mA	4.5 V	3.94			3.8	7	3.8		٧
Voi	I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V
VOL	I _{OL} = 8 mA	4.5 V			0.36	Q	0.44		0.44	V
lį	$V_I = V_{CC}$ or GND	0 V to 5.5 V			±0.1	7,	±1*		±1	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2	27/	20		20	μΑ
∆lcc‡	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35	P,40	1.5		1.5	mA
C _i	$V_I = V_{CC}$ or GND	5 V		2	10				10	pF

 $^{^{\}star}$ On products compliant to MIL-PRF-38535, this parameter is not production tested at V_{CC} = 0 V.

[‡] This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC}.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with JESD 51.

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timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

			$T_A = 2$	25°C	SN54AH	CT594	SN74AH	CT594	UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
	Pulse duration	RCLK or SRCLK high or low	5		5.5		5.5		ne	
t _W	Puise duration	RCLR or SRCLR low	5.2		5.5	F	5.5		ns	
		SER before SRCLK↑	3		3	14	3			
		SRCLK↑ before RCLK↑†	5		5.0		5		7	
t _{su}	Setup time	SRCLR low before RCLK↑	5		5		5		ns	
	SRCLR high (inactive) before SRCLK↑			3.3		3.3				
		RCLR high (inactive) before RCLK↑	3.4		3.8		3.8			
th	Hold time	SER after SRCLK↑	2		2		2		ns	

[†] This setup time allows the storage register to receive stable data from the shift register. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	չ = 25°C	;	SN54AH	CT594	SN74AH	CT594	UNIT
PARAWETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
f			C _L = 15 pF	135*	170*		115*		115		MHz
fmax			C _L = 50 pF	120	140		95		95		IVITIZ
^t PLH	DOL 14	0 0	C: - 15 pF		3.3*	6.2*	1*	6.5*	1	6.5	20
^t PHL	RCLK	Q _A –Q _H	C _L = 15 pF		3.7*	6.5*	1*	6.9*	1	6.9	ns
^t PLH	000114		C: - 15 pE		3.7*	6.8*	1*	7.2*	1	7.2	ns
^t PHL	SRCLK	CLK QH'	C _L = 15 pF		4.1*	7.2*	1*	7.6*	1	7.6	115
^t PHL	RCLR	Q _A –Q _H	C _L = 15 pF		4.5*	7.6*	1*,	8.2*	1	8.2	ns
^t PHL	SRCLR	$Q_{H'}$	C _L = 15 pF		4.1*	7.1*	3	7.6*	1	7.6	ns
^t PLH	DOLK.		C _I = 50 pF		4.9	7.8	01	8.3	1	8.3	ns
^t PHL	RCLK	Q _A –Q _H	CL = 50 pr		5.8	8.9	Q 1	9.7	1	9.7	115
^t PLH	000114		C _I = 50 pF		5.5	8.6	1	9.1	1	9.1	ns
^t PHL	SRCLK	Q _H ′	CL = 50 pr		6	9.2	1	10.1	1	10.1	115
^t PHL	RCLR	Q _A –Q _H	C _L = 50 pF		6.6	10	1	10.7	1	10.7	ns
^t PHL	SRCLR	Q _H ′	C _L = 50 pF		6	9.2	1	10.1	1	10.1	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, V_{CC} = 5 V, C_L = 50 pF, T_A = 25°C (see Note 4)

	PARAMETER				UNIT
	PARAMETER	MIN	TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		1		V
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.6		V
VOH(V)	Quiet output, minimum dynamic VOH		3.8		V
VIH(D)	High-level dynamic input voltage	2			V
V _{IL(D)}	Low-level dynamic input voltage			0.8	V

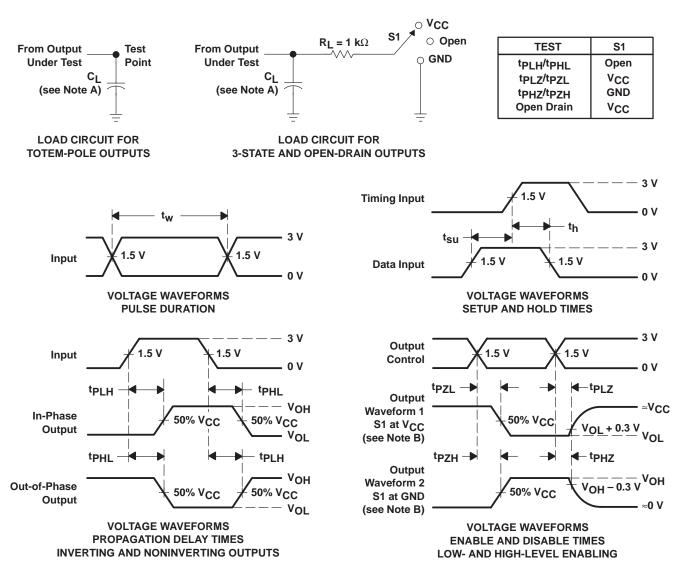
NOTE 4: Characteristics are for surface-mount packages only.



operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	No load, f = 1 MHz	112	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 3 ns. $t_f \leq$ 3 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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